



Substitute for forms 1449A/PTO & 1449B/PTO

**SECOND INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**ATTORNEY'S DKT NO.
001425-117APPLICATION NO.
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Hiroshi NogamiFILING DATE
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1700**RECEIVED**
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GROUP 1700**U.S. PATENT DOCUMENTS**

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MK	6-260434		Japan	09-16-1994	Abst.
MIC	5-21393		Japan	01-29-1993	Abst.

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
MK	Robert C. REID et al. "Lennard-Jones Potentials as Determined from Viscosity Data (Appendix B)", <i>The Properties of Gases and Liquids</i> , McGraw-Hill, Inc., Copyright 1987, p.734, Index
	R. Byron BIRD et al. "Diffusivity and the Mechanisms of Mass Transport; Theory of Ordinary Diffusion in Gases at Low Density", <i>Transport Phenomena</i> , John Wiley & Sons, Inc., Copyright 1960, p. 508-513
	A new technique for diagnostics of a radio-frequency parallel-plate remote plasma; N. Sano et al.; Appl. Phys. Lett 65 (2), 11 July 1994 pages 162-164.
	Infrared spectroscopic study of SiO _x films produced by plasma enhanced chemical vapor deposition; J. Vac.Sci. Technol. A4(3), May/June 1986; pages 689-694.
	Improvement of structural and electrical properties in low-temperature gate oxides for poly-Si TFTs by controlling O ₂ /SiH ₄ ratios; AM-LCD 1997; pages 87-90.
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Examiner Signature		Date Considered	06/12/03
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. **SEND TO:** Assistant Commissioner for Patents, Washington, DC 20231.